

**OptiMOS™3 Power-Transistor**
**Features**

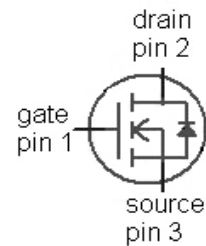
- Optimized technology for synchronous rectification
- Ideal for high frequency switching and DC/DC converters
- Excellent gate charge x  $R_{DS(on)}$  product (FOM)
- Very low on-resistance  $R_{DS(on)}$
- N-channel, normal level
- 100% avalanche tested
- Pb-free plating; RoHS compliant, halogen free
- Qualified according to JEDEC<sup>1)</sup> for target applications

**Product Summary**

|                  |     |    |
|------------------|-----|----|
| $V_{DS}$         | 75  | V  |
| $R_{DS(on),max}$ | 2.3 | mΩ |
| $I_D$            | 120 | A  |



| Type           | IPP023NE7N3 G | IPI023NE7N3 G |
|----------------|---------------|---------------|
|                |               |               |
| <b>Package</b> | PG-TO220-3    | PG-TO262-3    |
| <b>Marking</b> | 023NE7N       | 023NE7N       |


**Maximum ratings, at  $T_j=25\text{ °C}$ , unless otherwise specified**

| Parameter                                    | Symbol         | Conditions                                  | Value       | Unit |
|--|----------------|---|-------------|------|
| Continuous drain current                     | $I_D$          | $T_C=25\text{ °C}^{2)}$                     | 120         | A    |
|  |                | $T_C=100\text{ °C}$                         | 120         |      |
| Pulsed drain current <sup>2)</sup>           | $I_{D,pulse}$  | $T_C=25\text{ °C}$                          | 480         |      |
| Avalanche energy, single pulse <sup>3)</sup> | $E_{AS}$       | $I_D=100\text{ A}, R_{GS}=25\text{ }\Omega$ | 1100        | mJ   |
| Gate source voltage                          | $V_{GS}$       |   | $\pm 20$    | V    |
| Power dissipation                            | $P_{tot}$      | $T_C=25\text{ °C}$                          | 300         | W    |
| Operating and storage temperature            | $T_j, T_{stg}$ |   | -55 ... 175 | °C   |
| IEC climatic category; DIN IEC 68-1          |                |   | 55/175/56   |      |

<sup>1)</sup>J-STD20 and JESD22

<sup>2)</sup> See figure 3 for more detailed information

<sup>3)</sup> See figure 13 for more detailed information

| Parameter | Symbol | Conditions | Values |      |      | Unit |
|-----------|--------|------------|--------|------|------|------|
|           |        |            | min.   | typ. | max. |      |

**Thermal characteristics**

|  |            |  |   |   |     |     |
|--|------------|--|---|---|-----|-----|
| Thermal resistance, junction - case    | $R_{thJC}$ |  | - | - | 0.5 | K/W |
| Thermal resistance, junction - ambient | $R_{thJA}$ | minimal footprint                            | - | - | 62  |     |
|  |            | 6 cm <sup>2</sup> cooling area <sup>4)</sup> | - | - | 40  |     |

**Electrical characteristics**, at  $T_j=25\text{ °C}$ , unless otherwise specified

**Static characteristics**

|                                  |               |  |     |     |     |               |
|----------------------------------|---------------|--|-----|-----|-----|---------------|
| Drain-source breakdown voltage   | $V_{(BR)DSS}$ | $V_{GS}=0\text{ V}, I_D=1\text{ mA}$                       | 75  | -   | -   | V             |
| Gate threshold voltage           | $V_{GS(th)}$  | $V_{DS}=V_{GS}, I_D=273\text{ }\mu\text{A}$                | 2.3 | 3.1 | 3.8 |               |
| Zero gate voltage drain current  | $I_{DSS}$     | $V_{DS}=75\text{ V}, V_{GS}=0\text{ V}, T_j=25\text{ °C}$  | -   | 0.1 | 1   | $\mu\text{A}$ |
|                                  |               | $V_{DS}=75\text{ V}, V_{GS}=0\text{ V}, T_j=125\text{ °C}$ | -   | 10  | 100 |               |
| Gate-source leakage current      | $I_{GSS}$     | $V_{GS}=20\text{ V}, V_{DS}=0\text{ V}$                    | -   | 1   | 100 | nA            |
| Drain-source on-state resistance | $R_{DS(on)}$  | $V_{GS}=10\text{ V}, I_D=100\text{ A}$                     | -   | 2.1 | 2.3 | m $\Omega$    |
| Gate resistance                  | $R_G$         |  | -   | 2.7 | -   | $\Omega$      |
| Transconductance                 | $g_{fs}$      | $ V_{DS} >2 I_D R_{DS(on)max}, I_D=100\text{ A}$           | 98  | 195 | -   | S             |

<sup>4)</sup> Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm<sup>2</sup> (one layer, 70  $\mu\text{m}$  thick) copper area for drain connection. PCB is vertical in still air.

| Parameter | Symbol | Conditions | Values |      |      | Unit |
|-----------|--------|------------|--------|------|------|------|
|           |        |            | min.   | typ. | max. |      |

**Dynamic characteristics**

|                              |              |   |   |       |       |    |
|------------------------------|--------------|---|---|-------|-------|----|
| Input capacitance            | $C_{iss}$    | $V_{GS}=0\text{ V}, V_{DS}=37.5\text{ V},$<br>$f=1\text{ MHz}$                          | - | 10800 | 14400 | pF |
| Output capacitance           | $C_{oss}$    |   | - | 2420  | 3220  |    |
| Reverse transfer capacitance | $C_{rss}$    |   | - | 110   | -     |    |
| Turn-on delay time           | $t_{d(on)}$  | $V_{DD}=37.5\text{ V},$<br>$V_{GS}=10\text{ V}, I_D=100\text{ A},$<br>$R_G=1.6\ \Omega$ | - | 19    | -     | ns |
| Rise time                    | $t_r$        |   | - | 26    | -     |    |
| Turn-off delay time          | $t_{d(off)}$ |   | - | 70    | -     |    |
| Fall time                    | $t_f$        |   | - | 22    | -     |    |

**Gate Charge Characteristics<sup>5)</sup>**

|                       |               |  |   |     |     |    |
|-----------------------|---------------|--|---|-----|-----|----|
| Gate to source charge | $Q_{gs}$      | $V_{DD}=37.5\text{ V},$<br>$I_D=100\text{ A},$<br>$V_{GS}=0\text{ to }10\text{ V}$ | - | 54  | -   | nC |
| Gate to drain charge  | $Q_{gd}$      |  | - | 31  | -   |    |
| Switching charge      | $Q_{sw}$      |  | - | 51  | -   |    |
| Gate charge total     | $Q_g$         |  | - | 155 | 206 |    |
| Gate plateau voltage  | $V_{plateau}$ |  | - | 5.0 | -   |    |
| Output charge         | $Q_{oss}$     | $V_{DD}=37.5\text{ V}, V_{GS}=0\text{ V}$  | - | 160 | 212 | nC |

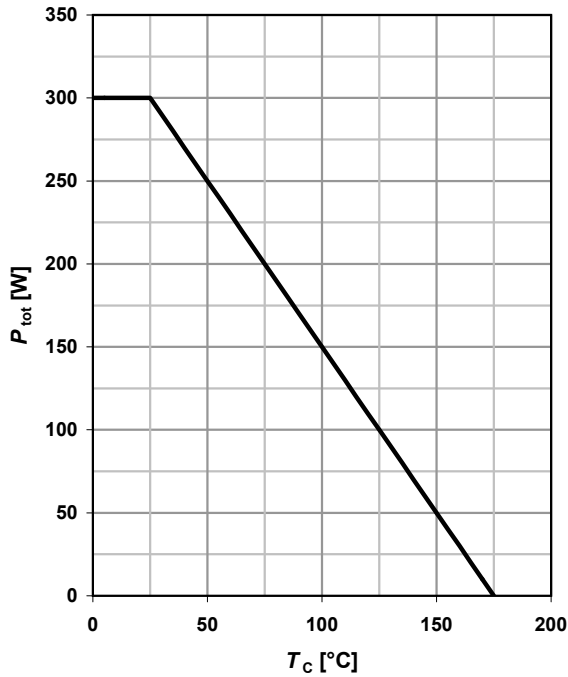
**Reverse Diode**

|                                  |               |  |   |     |     |    |
|----------------------------------|---------------|--|---|-----|-----|----|
| Diode continuous forward current | $I_S$         | $T_C=25\text{ }^\circ\text{C}$   | - | -   | 120 | A  |
| Diode pulse current              | $I_{S,pulse}$ |  | - | -   | 480 |    |
| Diode forward voltage            | $V_{SD}$      | $V_{GS}=0\text{ V}, I_F=100\text{ A},$<br>$T_j=25\text{ }^\circ\text{C}$ | - | 0.9 | 1.2 | V  |
| Reverse recovery time            | $t_{rr}$      | $V_R=37.5\text{ V}, I_F=I_S,$<br>$di_F/dt=100\text{ A}/\mu\text{s}$      | - | 72  | -   | ns |
| Reverse recovery charge          | $Q_{rr}$      |  | - | 129 | -   | nC |

<sup>5)</sup> See figure 16 for gate charge parameter definition

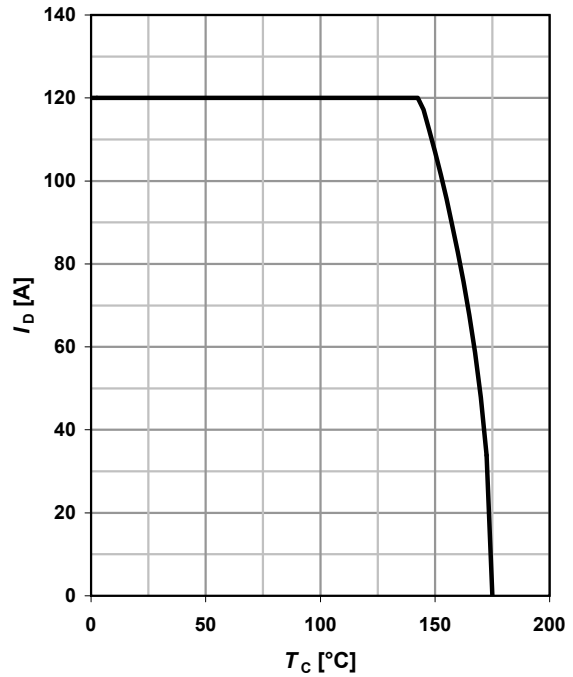
**1 Power dissipation**

$$P_{\text{tot}} = f(T_C)$$



**2 Drain current**

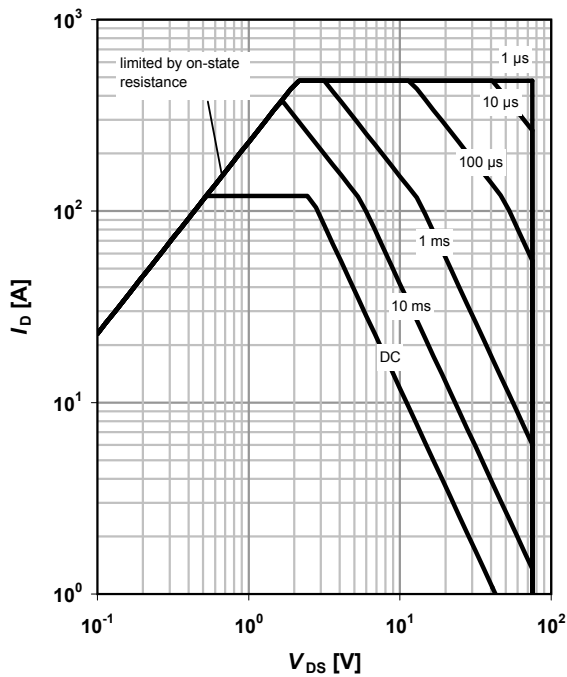
$$I_D = f(T_C); V_{GS} \geq 10 \text{ V}$$



**3 Safe operating area**

$$I_D = f(V_{DS}); T_C = 25 \text{ °C}; D = 0$$

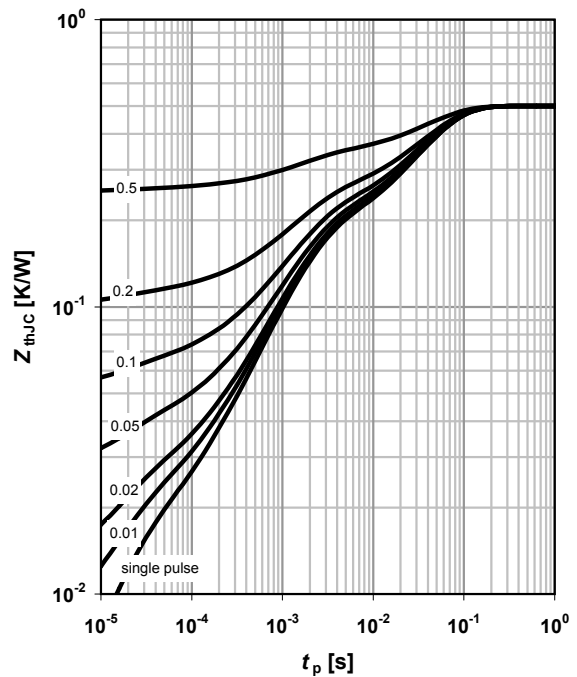
parameter:  $t_p$



**4 Max. transient thermal impedance**

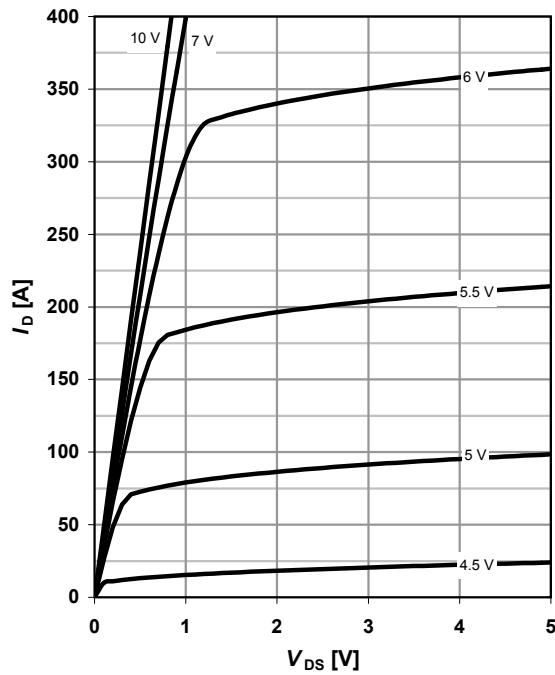
$$Z_{\text{thJC}} = f(t_p)$$

parameter:  $D = t_p / T$

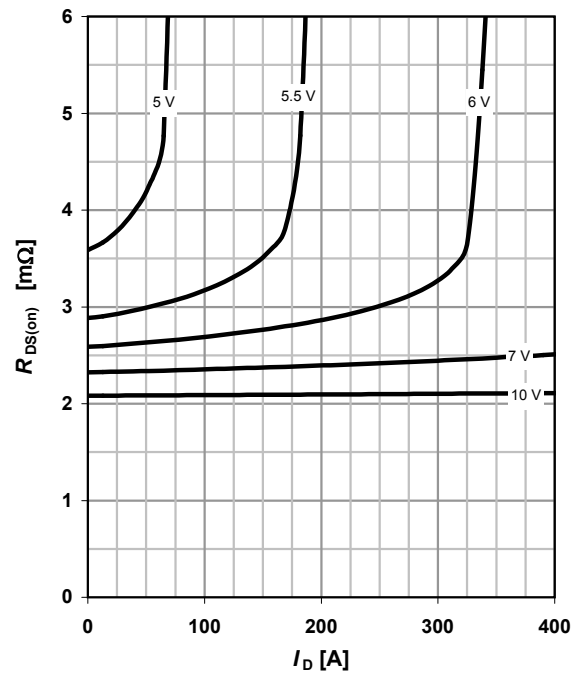


**5 Typ. output characteristics**

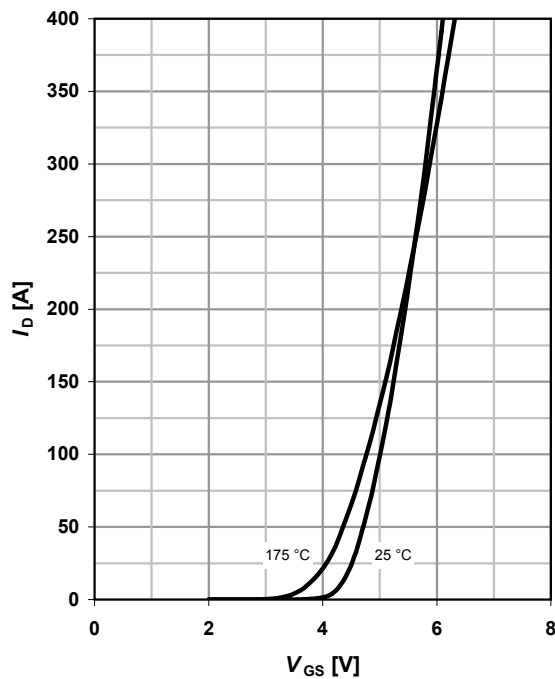
$$I_D = f(V_{DS}); T_j = 25\text{ °C}$$

 parameter:  $V_{GS}$ 

**6 Typ. drain-source on resistance**

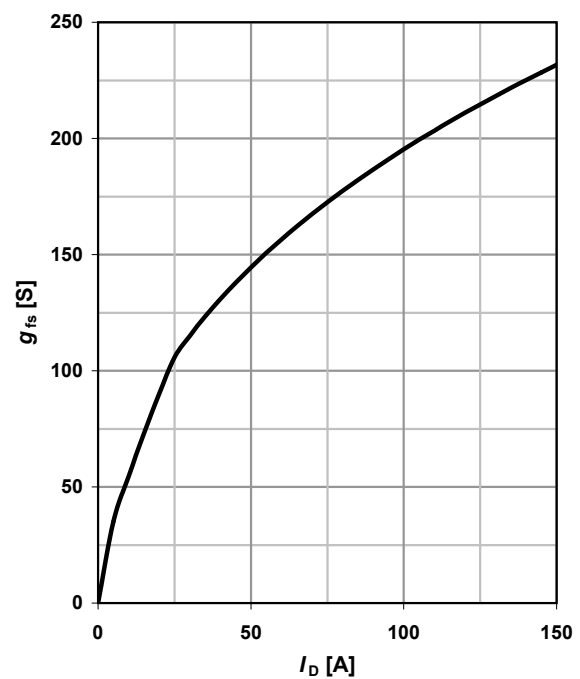
$$R_{DS(on)} = f(I_D); T_j = 25\text{ °C}$$

 parameter:  $V_{GS}$ 

**7 Typ. transfer characteristics**

$$I_D = f(V_{GS}); |V_{DS}| > 2|I_D|R_{DS(on)max}$$

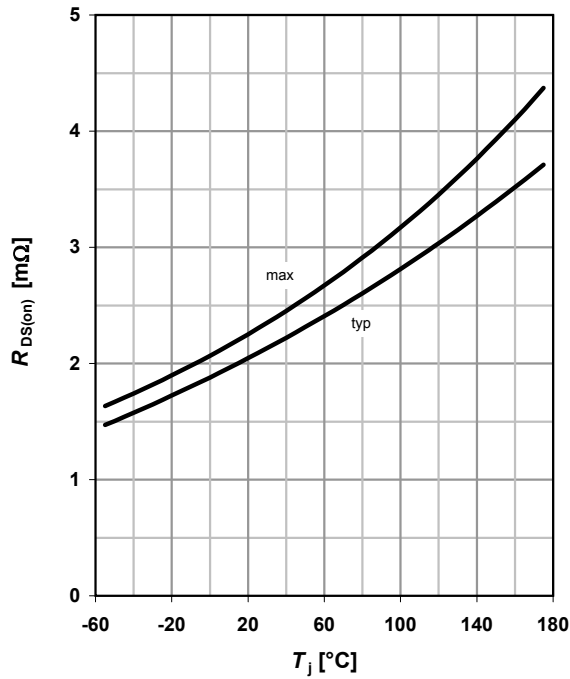
 parameter:  $T_j$ 

**8 Typ. forward transconductance**

$$g_{fs} = f(I_D); T_j = 25\text{ °C}$$

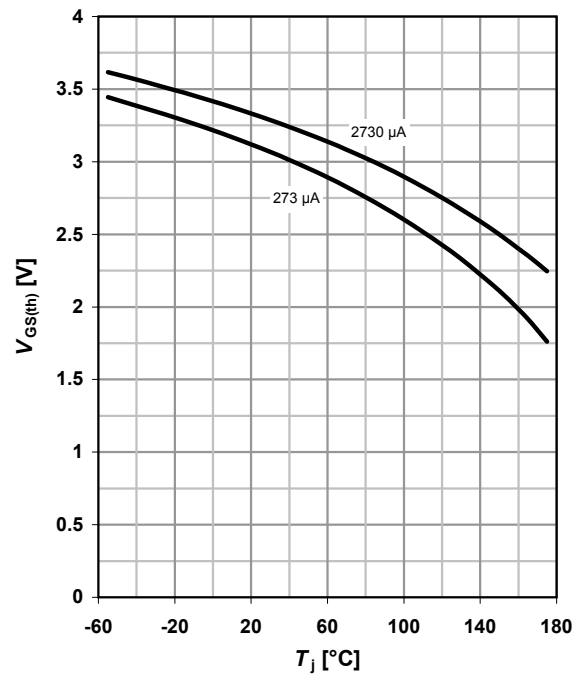


**9 Drain-source on-state resistance**

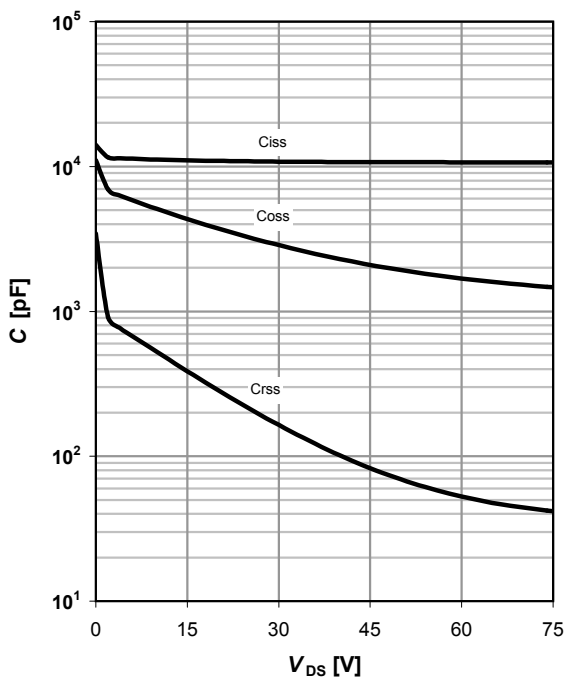
$$R_{DS(on)} = f(T_j); I_D = 100 \text{ A}; V_{GS} = 10 \text{ V}$$


**10 Typ. gate threshold voltage**

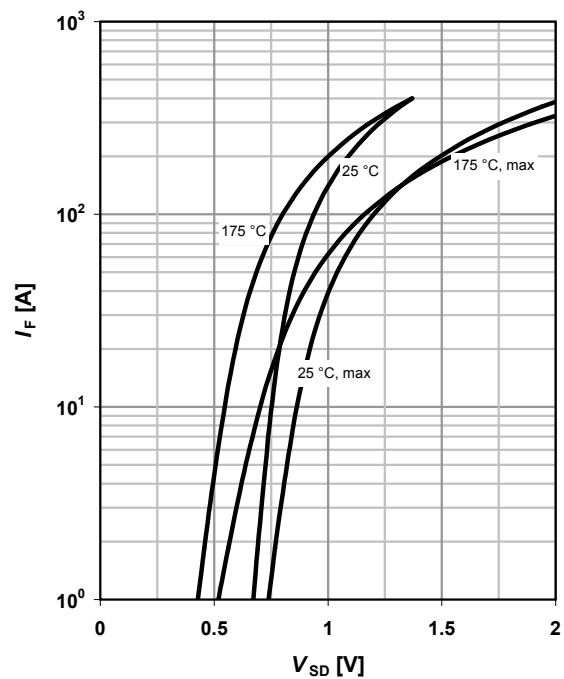
$$V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$$

 parameter:  $I_D$ 

**11 Typ. capacitances**

$$C = f(V_{DS}); V_{GS} = 0 \text{ V}; f = 1 \text{ MHz}$$


**12 Forward characteristics of reverse diode**

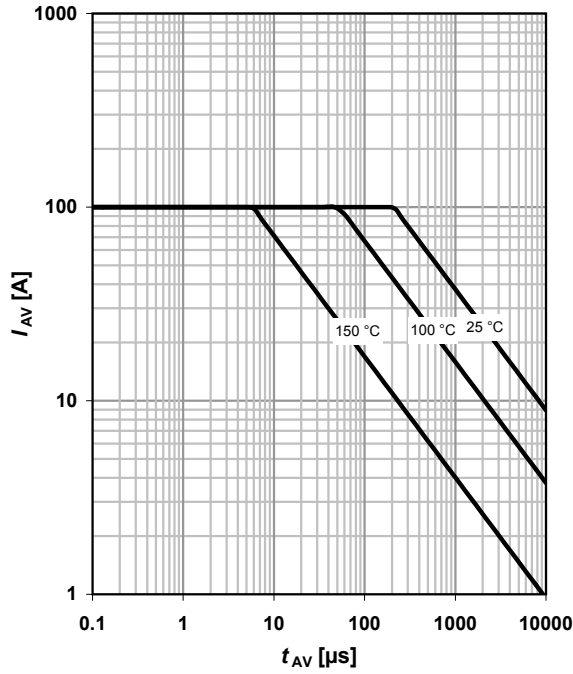
$$I_F = f(V_{SD})$$

 parameter:  $T_j$ 


**13 Avalanche characteristics**

$I_{AS}=f(t_{AV}); R_{GS}=25 \Omega$

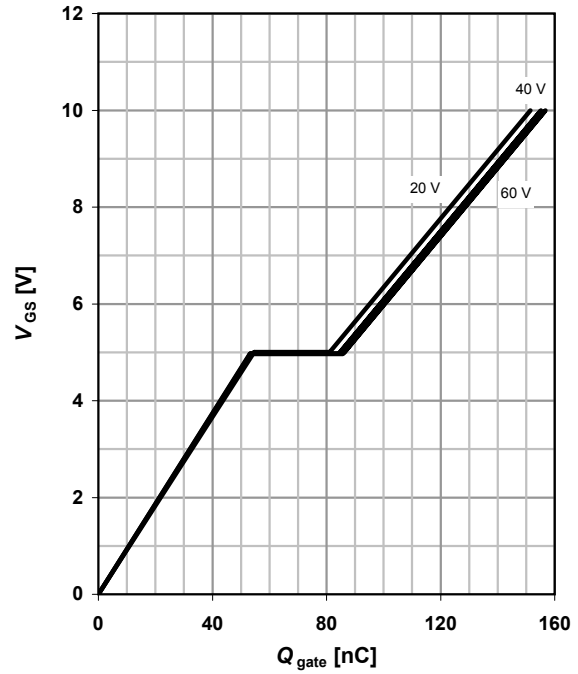
parameter:  $T_{j(start)}$



**14 Typ. gate charge**

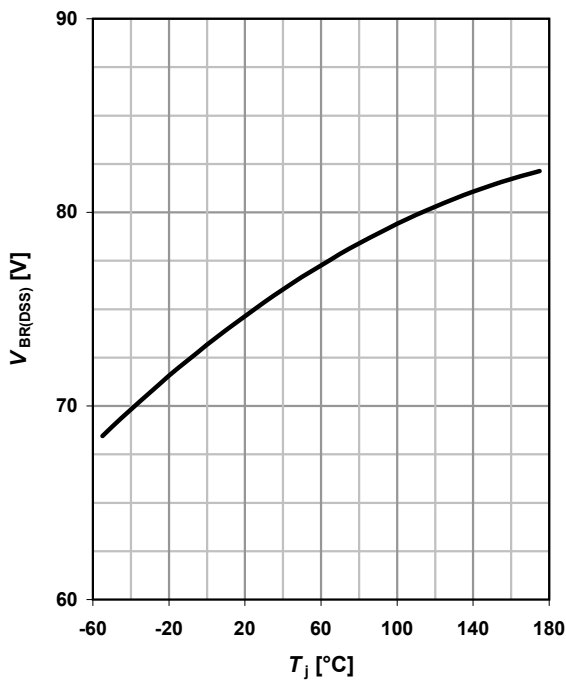
$V_{GS}=f(Q_{gate}); I_D=100 \text{ A pulsed}$

parameter:  $V_{DD}$

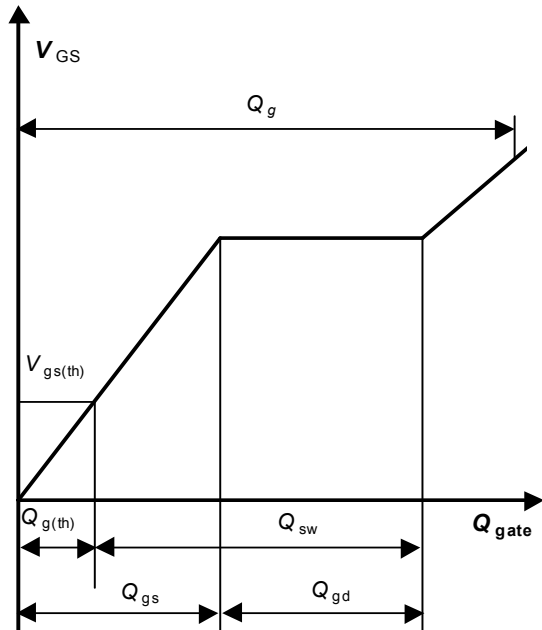


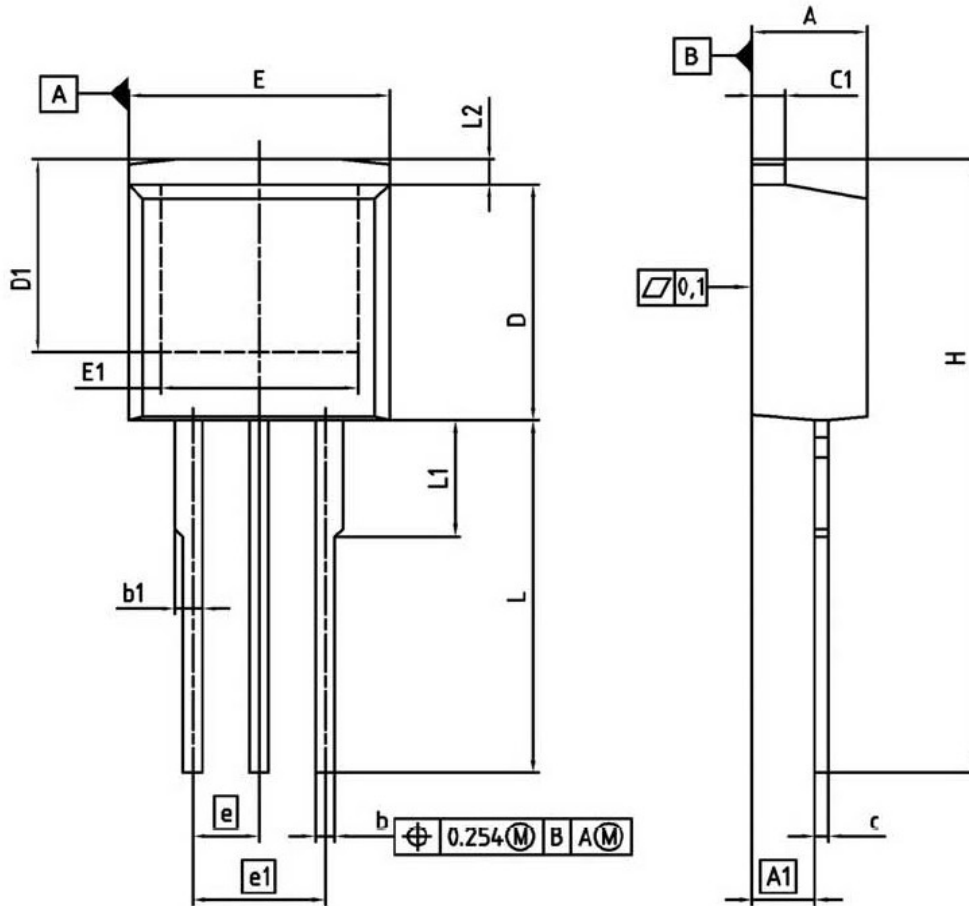
**15 Drain-source breakdown voltage**

$V_{BR(DSS)}=f(T_j); I_D=1 \text{ mA}$



**16 Gate charge waveforms**



PG-TO262-3 (I<sup>2</sup>-Pak)


| DIM | MILLIMETERS |        | INCHES |       |
|-----|-------------|--------|--------|-------|
|     | MIN         | MAX    | MIN    | MAX   |
| A   | 4.300       | 4.572  | 0.169  | 0.180 |
| A1  | 2.150       | 2.718  | 0.085  | 0.107 |
| b   | 0.650       | 0.664  | 0.026  | 0.034 |
| b1  | 0.635       | 1.400  | 0.025  | 0.055 |
| c   | 0.330       | 0.600  | 0.013  | 0.024 |
| c1  | 1.170       | 1.400  | 0.046  | 0.055 |
| D   | 8.509       | 9.450  | 0.335  | 0.372 |
| D1  | 6.900       | -      | 0.272  | -     |
| E   | 9.700       | 10.363 | 0.382  | 0.408 |
| E1  | 6.500       | 8.600  | 0.256  | 0.339 |
| e   | 2.540       |        | 0.100  |       |
| e1  | 5.080       |        | 0.200  |       |
| N   | 3           |        | 3      |       |
| L   | 13.000      | 14.000 | 0.512  | 0.551 |
| L1  | -           | 4.800  | -      | 0.189 |
| L2  | -           | 1.727  | -      | 0.068 |

REFERENCE  
JEDEC TO262

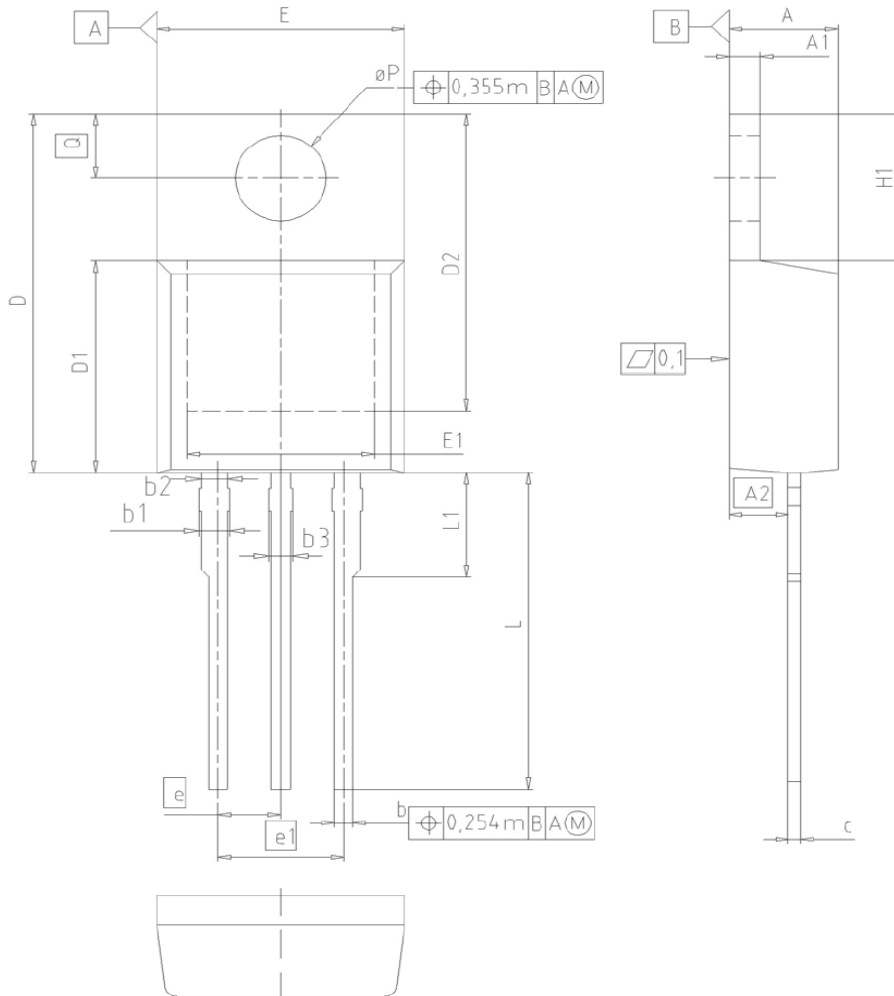
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PG-TO220-3



| DIM      | MILLIMETERS |       | INCHES |       |
|----------|-------------|-------|--------|-------|
|          | MIN         | MAX   | MIN    | MAX   |
| A        | 4.30        | 4.57  | 0.169  | 0.180 |
| A1       | 1.17        | 1.40  | 0.046  | 0.055 |
| A2       | 2.15        | 2.72  | 0.085  | 0.107 |
| b        | 0.65        | 0.86  | 0.026  | 0.034 |
| b1       | 0.95        | 1.40  | 0.037  | 0.055 |
| b2       | 0.95        | 1.15  | 0.037  | 0.045 |
| b3       | 0.65        | 1.15  | 0.026  | 0.045 |
| c        | 0.33        | 0.60  | 0.013  | 0.024 |
| D        | 14.81       | 15.95 | 0.583  | 0.628 |
| D1       | 8.51        | 9.45  | 0.335  | 0.372 |
| D2       | 12.19       | 13.10 | 0.480  | 0.516 |
| E        | 9.70        | 10.36 | 0.382  | 0.408 |
| E1       | 6.50        | 8.60  | 0.256  | 0.339 |
| e        | 2.54        |       | 0.100  |       |
| e1       | 5.08        |       | 0.200  |       |
| N        | 3           |       | 3      |       |
| H1       | 5.90        | 6.90  | 0.232  | 0.272 |
| L        | 13.00       | 14.00 | 0.512  | 0.551 |
| L1       | -           | 4.80  | -      | 0.189 |
| $\phi P$ | 3.60        | 3.89  | 0.142  | 0.153 |
| Q        | 2.60        | 3.00  | 0.102  | 0.118 |

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